Notice of References Cited 10/555,286 Reexamination JIMENEZ MAYORGA ET AL. Examiner SUN JAE Y. LOEWE Reexamination JIMENEZ MAYORGA ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	O	US-			
	D	US-			
	ш	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
-	Q					
	R					
	s					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Patani et al., Chem. Rev., 96, 3147-3176
	V	Fukui et al., caplus an 2002:142667
	w	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under